## Notice of References Cited Application/Control No. 09/449,016 Examiner KIEU-OANH BUI Applicant(s)/Patent Under Reexamination KAMEN ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0117527 A1	06-2003	Smith, Kim C.	348/565
*	В	US-2005/0283800 A1	12-2005	Ellis et al.	725/040
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	١	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
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	Р					
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## **NON-PATENT DOCUMENTS**

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